



## THE NEW LEVEL OF COATING THICKNESS MEASUREMENT AND MATERIAL ANALYSIS

Do you want maximum efficiency in your quality control? Do you have to measure coating thicknesses and material compositions highly precise? Our new FISCHERSCOPE® XDAL® with XRF technology and the cutting-edge FISIQ® X software is your solution!

### Super-fast sample positioning.

High-speed Z-axis 6 x faster\*

### Rapid sample capture.

Autofocus in under 2 seconds – 14 x faster\*

**Automated operation.** Automated or manual hood for maximum flexibility

### Unparalleled high precision and repeatable results.

Optimized measurement geometry

### Optimum sample illumination and picture capture.

10x higher\* camera resolution and multizone LED lighting

### Device status always visible.

Intuitive 180° status light

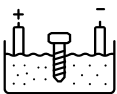
**Enhanced usability and user guidance.** New FISIQ® X software

**Large parts.** C-slot allows large part measurement

\*In comparison to FISCHERSCOPE® X-RAY XDAL® 237.

## Designed for an exceptionally wide range of applications

XRF multitalent for measuring thin and very thin layers <math><0.05 \mu\text{m}</math> and for material analysis in the ppm range, in many different industries.



### Electroplating & coating

Rely on precise measurements of functional and decorative coatings.



### PCB industry

Analyze ENIG/ENEPIG on PCBs with the highest accuracy.



### Defence

Measurements of special coating systems and high reliability electronics

Explore the new FISCHERSCOPE® XDAL®!

[glow-up.helmut-fischer.com](http://glow-up.helmut-fischer.com)



- ✓ Measure fast
- ✓ Measure precise
- ✓ Measure efficient

And many more...



FISCHER – globally leading in highly precise XRF measuring technology.

**fischer**®

Boost your productivity with simplified and efficient workflows

# FISIQ® X – THE FIRST XRF SOFTWARE WITH AI TECHNOLOGY

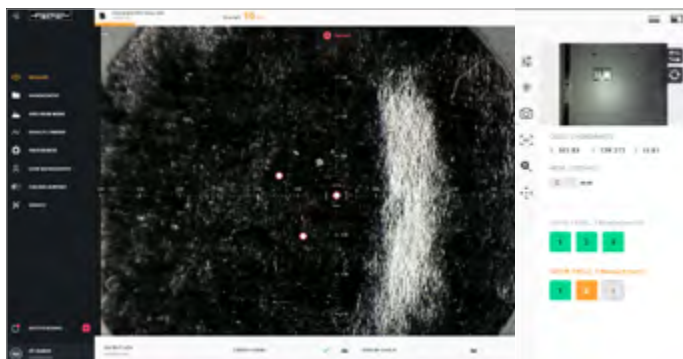


With our FISCHERSCOPE® XDAL® and FISIQ® X software, you measure coating thickness up to 6x faster\* and analyze materials up to 13x faster\* – thanks to improved algorithms and AI-supported spectrum analysis. Measure smarter, faster, and more user-friendly now!

- ✓ **Simplified and modern user interface**
- ✓ **Guided and efficient workflows**
- ✓ **Various user roles**

\*Comparison calculation time between WinFTM® 6 and FISIQ® X.

From inserting the sample to precise measuring results – in no time at all.



## 1. Calibrate quickly and easily.

Measure your standards with the simple and guided calibration workflow and benefit from the ready-to-use standard library.



## 3. Measure with full control.

Place your sample and start the measuring program. See a live image and all relevant information clearly displayed for instant insights.



## 2. Build secure workflows.

Predefine your measuring program effortlessly with drag-and-drop to enhance your process safety and ensure consistent, repeatable results.



## 4. Obtain your results, ready to use.

Get instant element identification, view all results at a glance, and generate your report in just a few clicks.



Experience the new measuring solution now!  
[fisiq-x.helmut-fischer.com](http://fisiq-x.helmut-fischer.com)